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Serial Number:

Appn. Filed:

Applicant(s): **ALEKSANDR L. YUFA**

Appn. Title:

**"METHODS AND WIRELESS COMMUNICATING APPARATUS FOR  
PRECISE ANALYZING OF ENVIRONMENT"**

Examiner:

Group Art Unit:

Mailed: January 29, 1998

At: COLTON, CALIFORNIA

**Information Disclosure Statement**

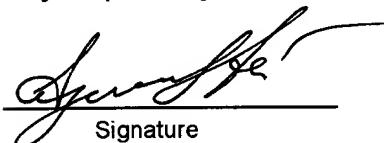
Assistant Commissioner for Patents  
Washington, District of Columbia 20231

Sir:

Attached is a completed Form PTO-1449 and copies of the pertinent parts of the references listed on this form. The comments on the relevance of any non-English references, pursuant to Rule 98 are contained in the Prior Art section of the specification.

Applied Form-1449 and the Pertinent Parts of the References 25 sheets

Very respectfully,

  
\_\_\_\_\_  
Signature

ALEKSANDR L. YUFA

Name

January 29, 1998

Date

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**OTHER PRIOR ART**  
(Including Author, Title, Date, Pertinent Pages, Etc.)

- AR** R.G.Knollenberg, B.Schuster--"Detection and Sizing of Small Particles in Open Cavity Gas Laser," Applied Optics, Vo.11, No.7, November 1972, pp.1515-1520;
- AS** R.G.Knollenberg--"An Active Scattering Aerosol Spectrometer," Atmospheric Technology, No.2, June 1973, pp.80-81;
- AR** Schehl, Ergun, Headrick--"Size Spectrometry of Aerosols Using Light Scattering from the Cavity of a Gas Laser," Review of Scientific Instruments, Vol. 44, No.9, September 1973.
- AS** R.G.Knollenberg--"Active Scattering Aerosol Spectrometry," National Bureau of Standards Special Publication, No.412, October 1974, pp.57-64;
- AR** R.G.Knollenberg, R.E.Luehr--"Open Cavity Laser 'Active' Scattering Particle Spectrometry from 0.05 to 5.0 Microns," Fine Particles, Aerosol Generation Measurement, Sampling and Analysis, Academic Press, May 1975, pp.669-696;
- AS** R.G.Knollenberg--"Three New Instruments for Cloud Physics Measurements: The 2-D Spectrometer, the Forward Scattering Spectrometer Probe, and the Active Scattering Aerosol Spectrometer", American Meteorological Society, International Conference on Cloud Physics, July 1976, pp. 554-561;
- AR** R.G.Knollenberg --"The Use of Low Power Laser in Particle Size Spectrometry", Proceeding of the Society of Photo-Optical Instrumentation Engineers, Practical Applications of Low Power Lasers, Vo.92, August 1976, pp.137-152;
- AS** Elterman "Brewster Angle Light Trap," Applied Optics, Vol. 16, No. 9, September 1977.

- AR** Marple--"The Aerodynamic Size Calibration of Optical Particle Counters by Inertial Impactor," *Aerosol Measurment*, 1979.
- AS** Diehl, Smith, Sydor--"Analysis of Suspended Solids by Single-Particle Scattering," *Applied Optics*, Vol. 18, No. 10, May 1979.
- AR** K.Suda--*Review of Scientific Instruments*, Vol. 51, No. 8, August 1980, pp.1049-1058.
- AS** R.G.Knollenberg--"The Measurement of Particle Sizes Below 0.1 Micrometers", *Journal of Environment Science*, January-February, 1985, pp. 64-67.
- AR** K.Sasaki, M.Koshioka, H.Misawa, M.Kitamura, H.Masuhara--"Laser-Scanning Micromanipulation and Spatial Patterning of Fine Particles", *Japanese Journal of Applied Physics*, Vo.30, No.5B, May 1991, pp.L907-L909.
- AS** K.Sasaki, M.Koshiok, H.Misawa, M.Kitamura--"Optical Trapping of a Metal Particle and a Water Droplet by a Scanning Laser Beam", *Applied Physics, Lett.*60 (7), American Institute Physics, February 17, 1992, pp.79-82.
- AR** Peters--"20 Good Reasons to Use In Situ Particle Monitors", *Semiconductor International*, November 1992, pp.52-57.
- AS** Busselman et al.--"In Situ Particle Monitoring in a Single Wafer Poly Silicon and Silicon Nitride Etch System", *IEEE/SEMI, Int'l Semiconductor Manufacturing Science Symposium*, 1993, pp.20-26.